

Special Issue

Technical Advances in Food and Agricultural Product Quality Detection

Message from the Guest Editors

The increasing demand for swift and precise quality assessment of food and agricultural products stems from the necessity to meet quality standards, uphold safety and hygiene protocols, and address concerns regarding food adulteration within the food supply chain. Regrettably, evaluating agricultural and food product quality still heavily relies on subjective measures, including visual inspection, consumer preference, and traditional wet chemistry methods, which can be labor-intensive, time-consuming, frequently unreliable, and require hazardous chemicals. Recent advancements in hardware design and data mining practices have unlocked the potential of new techniques and sensors as promising tools for routine analyses of agricultural and food products. This Special Issue aims to explore cutting-edge technological advancements that ensure quality and food safety in food and agricultural products. We invite original research articles, reviews, and short communications that delve into emerging device technologies, emphasizing miniaturization or their application for characterizing food products. Your contributions in this area are highly encouraged and welcomed.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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